FDR-control: Assumptions, a unifying proof, least favorable configurations and FDR-bounds

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Overview

Introduction

A Proof of FDR-Control

Critical value functions and rejection curves

SU FDR-bounds

SUD FDR-bounds

Reference:

Finner, H., Dickhaus, T. and Roters, M. (2007).

On the false discovery rate and an asymptotically optimal rejection curve.

Submitted for publication, in revision.



Notation & Definition of FDR

 Θ parameter space

$$H_1, \ldots, H_n$$
 null-hypotheses; p_1, \ldots, p_n p-values

 $\varphi_{(n)} = (\varphi_1, \ldots, \varphi_n)$ multiple test procedure

 $V_n = |\{i : \varphi_i = 1 \text{ and } H_i \text{ true }\}| = \text{number of true hypotheses rejected}$

 $R_n = |\{i : \varphi_i = 1\}|$ = number of hypotheses rejected

$$\mathsf{FDR}_{artheta}(arphi_{(n)}) = \mathbb{E}_{artheta}[rac{V_n}{R_n ee 1}]$$
 actual FDR given $artheta \in \Theta$

Definition. Let $\alpha \in (0, 1)$ be fixed.

 $\varphi_{(n)}$ controls the false discovery rate (FDR) at level α if

$$\mathsf{FDR}(\varphi_{(n)}) = \sup_{\vartheta \in \Theta} \mathsf{FDR}_{\vartheta}(\varphi_{(n)}) \leq \alpha.$$

The FDR-Theorem: Benjamini & Hochberg (1995)

$$H_i$$
 true for $i \in I_{n,0}$, H_i false for $i \in I_{n,1}$
 $I_{n,0} + I_{n,1} = I_n = \{1, \dots, n\}$, $n_0 = |I_{n,0}|$
 $p_i \sim U([0,1])$, $i \in I_{n,0}$, independent
 $(p_i : i \in I_{n,0})$, $(p_i : i \in I_{n,1})$ independent
 $p_{1:n} \leq \cdots \leq p_{n:n}$ ordered p-values

Linear step-up procedure $\varphi_{(n)}^{\text{LSU}}$ based on Simes' crit. val. $\alpha_{i:n} = i\alpha/n$:

Reject all H_i with $p_i \leq \alpha_{m:n}$, where $m = \max\{i : p_{i:n} \leq \alpha_{i:n}\}$.

Then

$$\mathsf{FDR}_{\vartheta}(\varphi_{(n)}^{\mathsf{LSU}}) = \mathbb{E}_{\vartheta}[\frac{V_n}{R_n \vee 1}] = \frac{n_0}{n}\alpha$$

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Linear step-up in terms of ecdf

Let F_n denote the empirical cdf (ecdf) of the p-values, that is,

$$F_n(t) = \frac{1}{n} \sum_{i=1}^n I_{[0,t]}(p_i).$$

Rejection curve: Simes-line defined by $r(t) = t/\alpha$.

Define

$$t^* = \sup\{t \in [0, \alpha] : F_n(t) \ge r(t)\}$$

and reject all H_i with $p_i \leq t^*$.

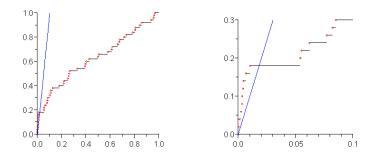
Call t^* the largest crossing point (LCP).



Simes-line and ecdf, $\alpha = 0.1$

$$X_i \sim N(\mu_i, 1), H_i : \mu_i = 0, i = 1, \dots, n,$$

 $n = 50, n_0 = 40, \zeta_n = n_0/n = 0.8, X_i \sim N(2, 1)$ for $i \in I_{n,1}$



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FDR-control under Dependency

- Benjamini, Y. & Yekutieli, D. (2001). The control of the false discovery rate in multiple testing under dependency. *Ann. Statist.* 29, 1165-1188.
- Sarkar, S. K. (2002). Some results on false discovery rate in stepwise multiple testing procedures. *Ann. Statist.* 30, 239-257.

FDR-control for special dependent test statistics:

$$\mathsf{FDR}_artheta(arphi_{(n)}) \leq rac{n_0}{n}lpha$$

Key assumptions: MTP₂ or PRDS



Linear step-up-down procedure (LSUD), Sarkar 2002

LSUD with parameter $\lambda \in [0, \alpha]$:

(1) $F_n(\lambda) \ge r(\lambda) \Rightarrow t^* = \inf\{p_i > \lambda : F_n(p_i) < f_\alpha(p_i)\}$ (SD-part). Reject all H_i with $p_i < t^*$.

(2) $F_n(\lambda) < r(\lambda) \Rightarrow t^* = \sup\{p_i < \lambda : F_n(p_i) \ge f_\alpha(p_i)\}$ (SU-part). Reject all H_i with $p_i \le t^*$.

Remark: SU for $\lambda = \alpha$ and SD for $\lambda = 0$



Proof: FDR-control for SU, SD and SUD ($\alpha_{j:n} = j\alpha/n$)

$$\begin{aligned} \mathsf{FDR}_{\vartheta}(\varphi) &= \mathbb{E}_{\vartheta}\left[\frac{V_n}{R_n \vee 1}\right] \\ &= \sum_{i \in I_{n,0}} \sum_{j \in I_n} \frac{1}{j} \, P_{\vartheta}(R_n = j, \varphi_i = 1) \\ &= \sum_{i \in I_{n,0}} \sum_{j \in I_n} \left[\frac{1}{j} \, P_{\vartheta}(p_i \leq \alpha_{j:n}) \cdot P_{\vartheta}(R_n = j \mid p_i \leq \alpha_{j:n})\right] \\ &\leq \sum_{i \in I_{n,0}} \sum_{j \in I_n} \frac{\alpha_{j:n}}{j} \, P_{\vartheta}(R_n = j \mid p_i \leq \alpha_{j:n}) \\ &\leq \sum_{i \in I_{n,0}} [\alpha_{1:n} \, P_{\vartheta}(R_n \geq 1 \mid p_i \leq \alpha_{1:n}) \\ &+ \sum_{j=2}^n \left(\frac{\alpha_{j:n}}{j} - \frac{\alpha_{j-1:n}}{j-1}\right) \, P_{\vartheta}(R_n \geq j \mid p_i \leq \alpha_{j:n}) \right] \\ &\leq \frac{n}{(ii)} \, \frac{n_0}{n} \alpha. \end{aligned}$$

Proof: FDR-control for SU, SD and SUD ($\alpha_{j:n} = j\alpha/n$)

ad (i): "=" holds if
$$p_i \sim U(0, 1), i \in I_{n,0}$$
.
ad (ii): " \leq " holds if
(1) $\forall i \in I_{n,0} : P_{\vartheta}(R_n \geq j \mid p_i \leq t)$ is non-increasing in $t \in (0, \alpha_{j:n}]$.
"=" holds if $\begin{cases} \varphi \text{ is a LSU-test,} \\ p_i, i \in I_{n,0}, \text{ iid,} \\ (p_i :\in I_{n,0}), (p_i :\in I_{n,1}) \text{ independent.} \end{cases}$

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ad (iii): (iii) holds if $\forall i \in I_{n,0}$: $P_{\vartheta}(R_n \ge 1 \mid p_i \le \alpha_{1:n}) = 1$.

Note: MTP₂ or PRDS implies (1).

Condition (1)

Condition (1) is the most important assumption and applicable for SU- and SUD-tests.

(1) $\forall i \in I_{n,0} : P_{\vartheta}(R_n \ge j \mid p_i \le t)$ is non-increasing in $t \in (0, \alpha_{j:n}]$.

Suppose that the p_i 's , $i \in I_{n,0}$ are iid uniform and $(p_i :\in I_{n,0})$, $(p_i :\in I_{n,1})$ are independent.

Then, we have for SU-tests that

 $\forall i \in I_{n,0} : P_{\vartheta}(R_n \ge j \mid p_i \le t)$ is constant in $t \in (0, \alpha_{j:n}]$.

For SUD-test,

 $P_{\vartheta}(R_n \ge j \mid p_i \le t)$ is typically decreasing in $t \in (0, \alpha_{j:n}]$.



Introduction A Proof of FDR-Control

SUD FDR-bounds

Question

What happens with the FDR if we use

non-linear critical values / a non-linear rejection curve

for a SU- or SUD-procedure of order $\lambda < 1$?



Critical value functions

Let $\rho : [0, 1] \rightarrow [0, 1]$ be non-decreasing and continuous with $\rho(0) = 0$ and positive values on (0, 1].

Define critical values

$$\alpha_{i:n} = \rho(i/n) \in (0, 1], \ i = 1, \dots, n.$$

We call ρ a critical value function.

Define r by

 $r(x) = \inf\{u \in [0,1] : \rho(u) = x\} \text{ for } x \in [0,1] \text{ (with } \inf \emptyset = \infty).$

We call r a rejection curve.

Often: $r(x) = \rho^{-1}(x)$.



SU based on ρ

From Benjamini and Yekutieli (2001) we get the following.

Consider a SU-procedure based on ρ .

If $\rho(x)/x$ is non-decreasing in $x \in (0, 1]$ and if the p_i 's under the nulls are iid uniform and independent of the alternative *p*-values,

then the FDR is largest if $p_i = 0$ a.s. for all alternative *p*-values,

i.e., Dirac-uniform configurations are least favorable (LFC) for the FDR.

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FDR bound for SU

Let $\vartheta \in \Theta$ such that $n_0 = |I_{n,0}| =$ number of true nulls.

 $I_{n,0}'=I_{n,0}\setminus\{i_0\}$ for some $i_0\in I_{n,0}.$

Then the FDR of the SU-test $\varphi_{(n)}^{SU,\rho}$ based on ρ is bounded by

$$\mathsf{FDR}_{artheta}(arphi_{(n)}^{\mathsf{SU},
ho}) \leq rac{n_0}{n} \mathbb{E}_{I_{n,0}'}\left[rac{
ho(R_n/n)}{R_n/n}
ight],$$

with " = " for the Dirac-uniform configuration.

Moreover, if

$$\lim_{n \to \infty} \frac{n_0}{n} = \zeta$$
 and $\lim_{n \to \infty} \frac{R_n}{n} = \gamma_{\zeta}$ a.s. (w.r.t. DU),

then the FDR is asymptotically bounded by

$$\zeta \frac{\rho(\gamma_{\zeta})}{\gamma_{\zeta}}.$$

Idea: Optimize ρ for a SU procedure

Try to find a ρ such that

$$\zeta \frac{\rho(\gamma_{\zeta})}{\gamma_{\zeta}} \equiv \min\{\zeta, \alpha\}$$

for as many ζ 's as possible !

In other words, try to find a SU-test such that the FDR-level α is (asymptotically) exhausted under DU-configurations.

Solution:

In the next talk by Thorsten Dickhaus.



FDR bound for SUD(λ)

Let $\vartheta \in \Theta$ such that n_0 = number of true nulls.

$$I_{n,0}' = I_{n,0} \setminus \{i_0\}$$
 for some $i_0 \in I_{n,0}$.

Then the FDR of the SUD-test $\varphi_{(n)}^{SUD,\rho}$ based on ρ is bounded by

$$\mathsf{FDR}_artheta(arphi_{(n)}^{\mathsf{SUD},
ho}) \leq rac{n_0}{n} \mathbb{E}_{I_{n,0}'}\left[rac{
ho(R_n/n)}{R_n/n}
ight]$$

This bound is not sharp for SUD ($\lambda < 1$).

However, if

$$\lim_{n\to\infty}\frac{n_0}{n}=\zeta \text{ and } \lim_{n\to\infty}\frac{R_n}{n}=\gamma_{\zeta} \text{ a.s. (w.r.t. DU)},$$

then the FDR is asymptotically sharply bounded by

$$\zeta \frac{\rho(\gamma_{\zeta})}{\gamma_{\zeta}}.$$

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Now: Optimize ρ for a SUD procedure

Try to find a ρ such that

$$\zeta \frac{\rho(\gamma_{\zeta})}{\gamma_{\zeta}} \equiv \min\{\zeta, \alpha\}$$

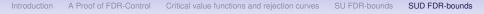
for as many ζ 's as possible !

In other words, try to find a SUD-test such that the FDR-level α is exhausted under DU-configurations.

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Optimal procedure ?

Does there exist an

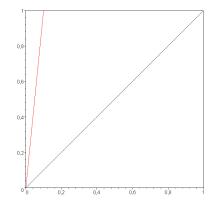
asymptotically optimal rejection curve ?

Does there exist an

asymptotically optimal SU- or SUD-procedure ?

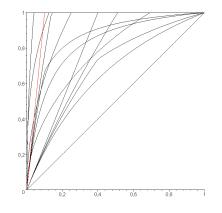


Which rejection curve is optimal?



Which rejection curve is optimal ?

There are so many other curves $r : [0, 1] \rightarrow [0, 1]$!



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